

## ABSTRACT OF THE DISCLOSURE:

**TITLE:       SYSTEM FOR TESTING MULTIPLE GROUPS OF IC-CHIPS  
              WHICH CONCURRENTLY SENDS TIME-SHIFTED TEST  
              SIGNALS TO THE GROUPS**

          An electromechanical system for testing IC-chips includes a total of  $N$  chip holding subassemblies; a moving mechanism for automatically moving the  $i$ -th chip holding subassembly from a load position in the system to  
5   the test position in the system, and visa-versa, where  $i$  ranges from 1 to  $N$  and changes with time in a sequence; and a signal generator which sends test signals to the IC-chips at the test position. Between the moving of the  $i$ -th chip holding subassembly and the next subassembly in  
10   the sequence, test signals are sent to the IC-chips on all  $N$  of the chip holding subassemblies such that the signals are shifted in time from one subassembly to another. Also, while the  $i$ -th chip holding subassembly is being moved, the time shifted test signals continue to  
15   be sent to the IC-chips on the remaining  $N-1$  chip holding subassemblies.